IXYS

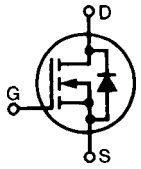
HiPerFET™ Power MOSFETs Q-Class

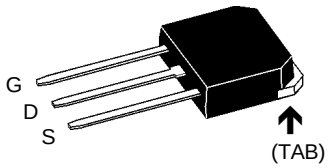
IXFJ 32N50Q

V_{DSS} = 500 V
$I_{D(cont)}$ = 32 A
$R_{DS(on)}$ = 0.15 Ω
t_{rr} < 250 ns

N-Channel Enhancement Mode
Avalanche Rated
High dv/dt, Low t_{rr}, HDMOS™ Family

Preliminary data sheet





G = Gate, D = Drain,
S = Source, TAB = Drain

Symbol	Test Conditions	Maximum Ratings	
V_{DSS}	T_J = 25°C to 150°C	500	V
V_{DGR}	T_J = 25°C to 150°C; R_{GS} = 1 MΩ	500	V
V_{GS}	Continuous	±20	V
V_{GSM}	Transient	±30	V
I_{D25}	T_C = 25°C	32	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	128	A
I_{AR}	T_C = 25°C	32	A
E_{As}	T_C = 25°C	1.5	J
E_{AR}	T_C = 25°C	45	mJ
dv/dt	$I_S \le I_{DM}$, di/dt ≤ 100 A/μs, $V_{DD} \le V_{DSS}$, $T_J \le$ 150°C, R_G = 2 Ω	5	V/ns
P_D	T_C = 25°C	360	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C

Features

- Low profile, high power package
- Long creep and strike distances
- Easy up-grade path for TO-220 designs
- Low $R_{DS\ (on)}$ low Qg process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
  - easy to drive and to protect
- Fast intrinsic Rectifier

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
V_{DSS}	V_{GS} = 0 V, I_D = 250 μA	500			V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 4 mA	2		4	V
I_{GSS}	V_{GS} = ±20 V_{DC}, V_{DS} = 0			±100	nA
I_{DSS}	$V_{DS} = V_{DSS}$, V_{GS} = 0 V; T_J = 25°C			100	μA
	T_J = 125°C			1	mA
$R_{DS(on)}$	V_{GS} = 10 V, $I_D = 0.5\ I_{D25}$ Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			0.15	Ω

Applications

- DC-DC converters
- Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control
- Temperature and lighting controls
- Low voltage relays

Advantages

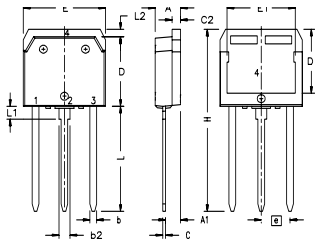
- High power, low profile package
- Space savings
- High power density

Symbol	Test Conditions (T_J = 25°C, unless otherwise specified)	min.	typ.	max.	
g_{fs}	V_{DS} = 10 V; I_D = 0.5 I_{D25}, pulse test	18	28		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		3950		pF
C_{oss}			640		pF
C_{rss}			210		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 I_{D25} R_G = 2 Ω (External)		35		ns
t_r			42		ns
$t_{d(off)}$			75		ns
t_f			20		ns
$Q_{g(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 I_{D25}		153		nC
Q_{gs}			26		nC
Q_{gd}			85		nC
R_{thJC}				0.35	K/W
R_{thCK}			0.25		K/W

Source-Drain Diode

Symbol	Test Conditions (T_J = 25°C, unless otherwise specified)	min.	typ.	max.	
I_S	V_{GS} = 0 V			32	A
I_{SM}	Repetitive; pulse width limited by T_{JM}			128	A
V_{SD}	I_F = I_S, V_{GS} = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			1.5	V
t_{rr}	I_F = I_S -di/dt = 100 A/μs, V_R = 100 V			250	ns
Q_{rr}			0.75		μC
I_{RM}			7.5		A

TO-268 Outline



All metal area are solder plated
1 - gate
2 - drain (collector)
3 - source (emitter)
4 - drain (collector)

Dim.	Inches Min	Inches Max	Millimeters Min	Millimeters Max
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
C	.016	.026	.040	.065
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215 BSC		5.45 BSC	
H	1.365	1.395	34.67	35.43
L	.780	.800	19.81	20.32
L1	.079	.091	2.00	2.30
L2	.039	.045	1.00	1.15

Figure 1. Output Characteristics at 25°C

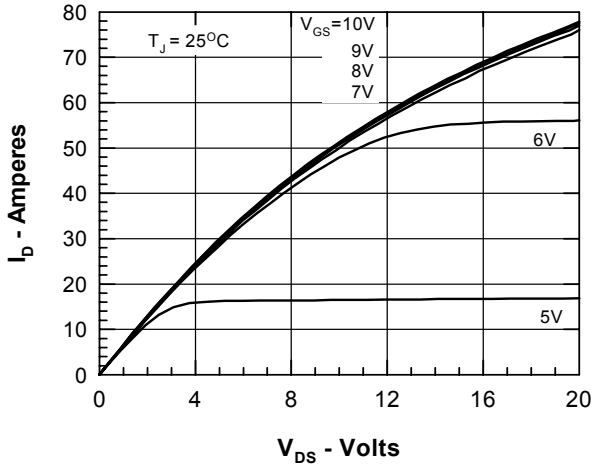


Figure 2. Output Characteristics at 125°C

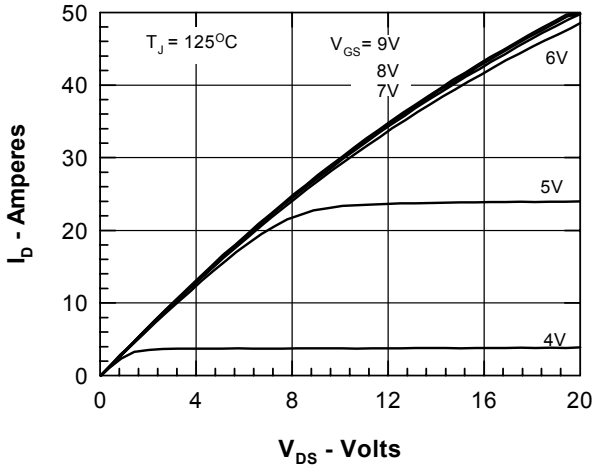


Figure 3. $R_{DS(on)}$ normalized to 15A/25°C vs. I_D

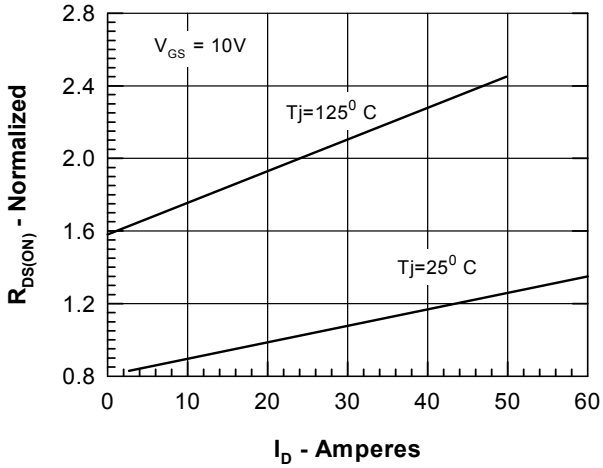


Figure 4. $R_{DS(on)}$ normalized to 15A/25°C vs. T_J

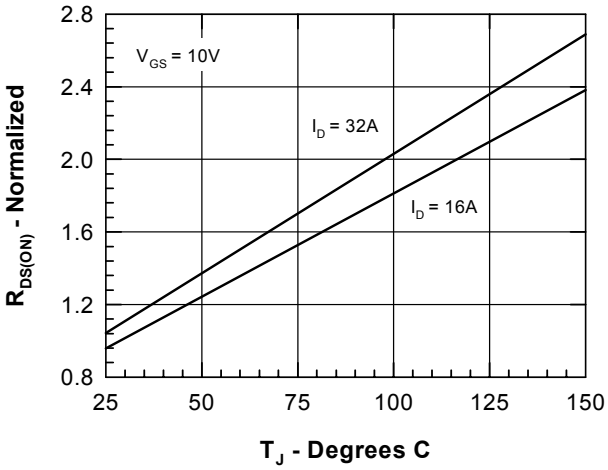


Figure 5. Drain Current vs. Case Temperature

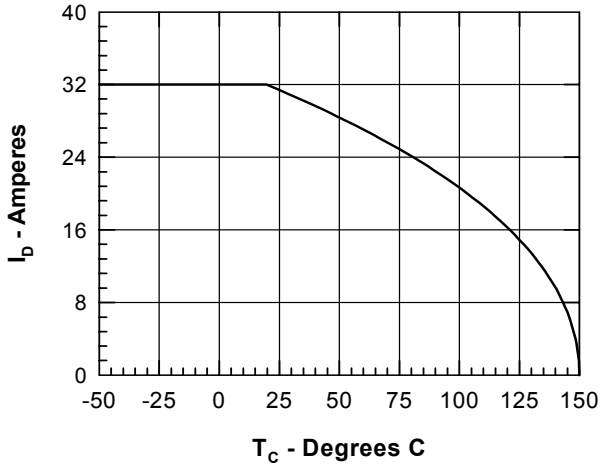


Figure 6. Admittance Curves

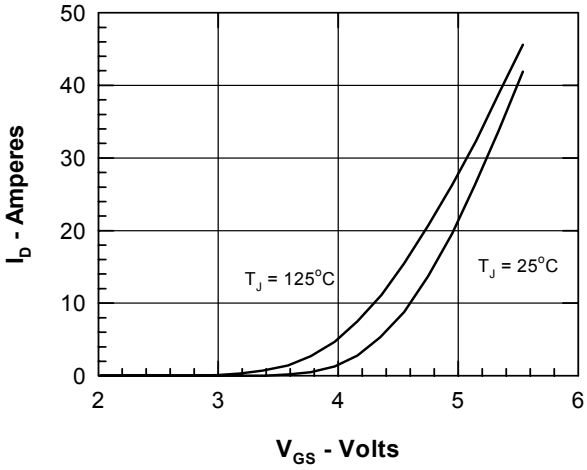


Figure 7. Gate Charge

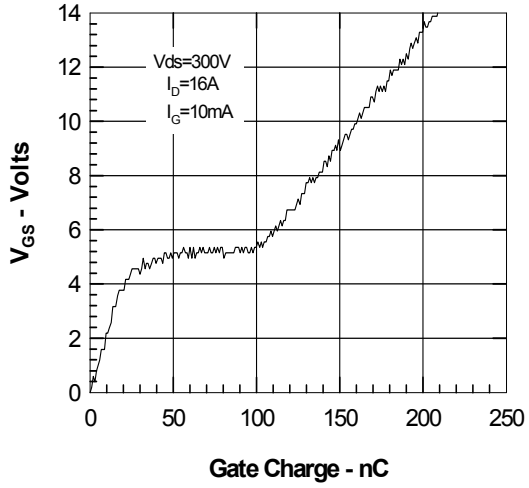


Figure 8. Capacitance Curves

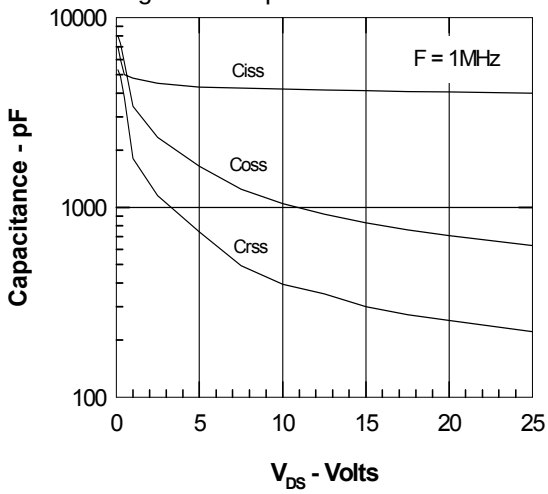


Figure 9. Forward Voltage Drop of the Intrinsic Diode

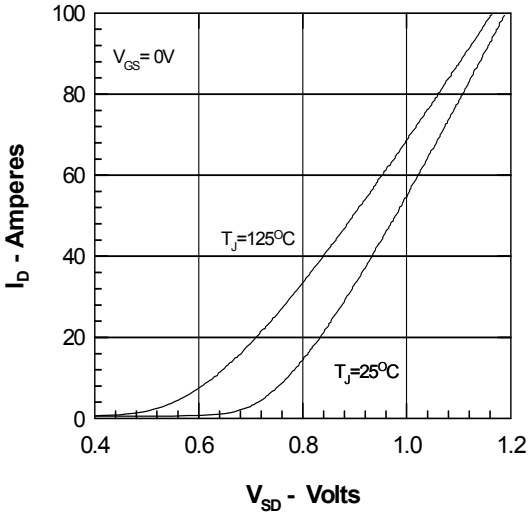


Figure 10. Transient Thermal Resistance